ICMOVPE
XXII July 12-17, 2026
ICC JEJU, Jeju Island, Korea

Session Title:	**[ThB1] Structural Analysis**
Session Date:	**July 16 (Thu.), 2026**
Session Time:	**08:30-10:15**
Session Room:	**Room B (Baekrok Hall B-2, 1F)**
Session Chairs	

[ThB1-1] [Invited] **08:30-09:00**

MOVPE Growth of AlGaN with Step-and-Terrace Structures on AlN Templates

Ryota Akaike, Hiroki Yasunaga, Takao Nakamura, and Hideto Miyake, Mie University, Japan

[ThB1-2] **09:00-09:15**

Atomic Structure of Antiphase Domain Boundaries in III-V Semiconductor Layers Epitaxially Grown on Silicon (100) or Obtained by Direct Wafer Bonding

Gilles Patriarche[1], Konstantinos Pantzas[1], Alexandre Beck[2], Laurent Pedesseau[2], Rozenn Gautheron-Bernard[2], Nathaniel Findling[1], Ludovic Largeau[1], Grégoire Beaudoin[1], Jean-Baptiste Rodriguez[3], Eric Tournié[3], Isabelle Sagnes[1], and Charles Cornet[2], [1] Centre national de la recherche scientifique, France, [2] Institut National des Sciences Appliquées de Rennes , France, [3] Université de Montpellier, France

[ThB1-3] **09:15-09:30**

Interplay of Carrier Recombination and Separation in an InGaN MQW LED Investigated by Nano-STEM-EBIC and -STEM-CL

Niklas Dreyer, Frank Bertram, Gordon Schmidt, Luca Greczmiel, Christoph Berger, Armin Dadgar, André Strittmatter, and Jürgen Christen, Otto-von-Guericke-University Magdeburg, Germany

[ThB1-4] **09:30-09:45**

Vacancy Properties and Their Clustering in GaN MOVPE Epitaxial Layers and Heterostructures

Alice Hospodková[1], Jakub Čížek[2], František Hájek[1], Karla Kuldová[1], Tomáš Hubáček[1], Jiří Pangrác[1], Maciej Oskar Liedke[3], Eric Hirschmann[3], Maik Butterling[3], and Andreas Wagner[3], [1] Institute of Physics of the Czech Academy of Sciences, Czech Republic, [2] Charles University, Czech Republic, [3] Helmholtz-Zentrum Dresden-Rossendorf, Germany

[ThB1-5] **09:45-10:00**

Revisiting the Stacking Faults in 4H-SiC

Soon-Ku Hong[1], Moonkyong Na[2], Hyundon Jung[3], and Wook Bahng[2], [1] Chungnam National University, Korea, [2] Korea Electrotechnology Research Institute, Korea, [3] Horiba STEC Korea, Korea

[ThB1-6] **10:00-10:15**

Analytical X-Ray Solutions for Thin Film and Wafer Analysis

Andrey Zameshin[1], Alexey Pustovarenko[1], Amardeep Bharti[1], Choong Ki (Daniel) Lee[2], and Shuji Kusano[3], [1] Malvern Panalytical, Netherlands, [2] Spectris Korea Ltd, Korea, [3] Spectris Co. Ltd, Japan